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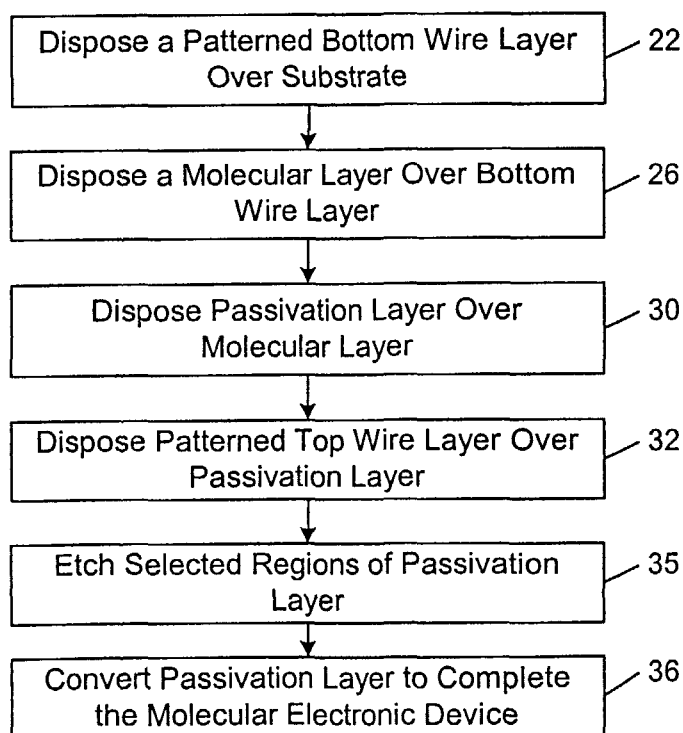
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(54) Title: PASSIVATION LAYER FOR MOLECULAR ELECTRONIC DEVICE FABRICATION



(57) Abstract: A process of fabricating a molecular electronic device that preserves the integrity of the active molecular layer of the electronic device during processing is described. In one aspect, a passivation layer is provided to protect a molecular layer from degradation during patterning of the top wire layer. A molecular electronic device structure and a memory system that are formed from this fabrication process are described.



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